

**Amendments to the Abstract:**

Please replace the Abstract at paragraph [0028] with the following Abstract:

**ABSTRACT OF THE DISCLOSURE**

[0028] The present invention provides a method and an apparatus for evaluating the surfaces of substrates for three dimensional defects. The present invention uses ~~low-angled~~ low-angled lighting positioned on opposite sides of the substrate. A ~~camera~~, camera positioned above the substrate captures two images thereof, one using the first light ~~source~~, source and one using the second. The first and second images are subtracted from one another to create a third image. Camera data suggestive of three dimensional features is emphasized by subtracting the two images and can be evaluated. A fourth image may be created by selecting the minimum values between the first and second images on a ~~point-by-point~~ point-by-point basis. The fourth image also provides useful information in evaluating three dimensional defects.